

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	fuse same semiconductor same locat\$4 same memory same (defect\$4fail\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/04/15 13:54
L2	106	fuse same semiconductor same locat\$4 same memory same (defect\$4 fail\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/04/15 13:54
L3	62	semiconductor same fuse with locat\$4 same memory same (defect\$4 fail\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/04/15 13:55
L4	2457	test\$4 with fuses!3 same semiconductor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/04/15 13:55
L5	371	test\$4 with fuses! same semiconductor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/04/15 13:56
L6	15	test\$4 with fuses! same semiconductor and memory same location same defect\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/04/15 13:58
L7	3	test\$4 near fuses! same semiconductor and memory same location same defect\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/04/15 13:59
L8	14	test\$4 near fuses! same semiconductor and memory same fuse same defect\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/04/15 13:59
L9	12	test\$4 near fuses! same semiconductor and memory same fuse same defect\$4 and fuse.ti.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/04/15 13:59